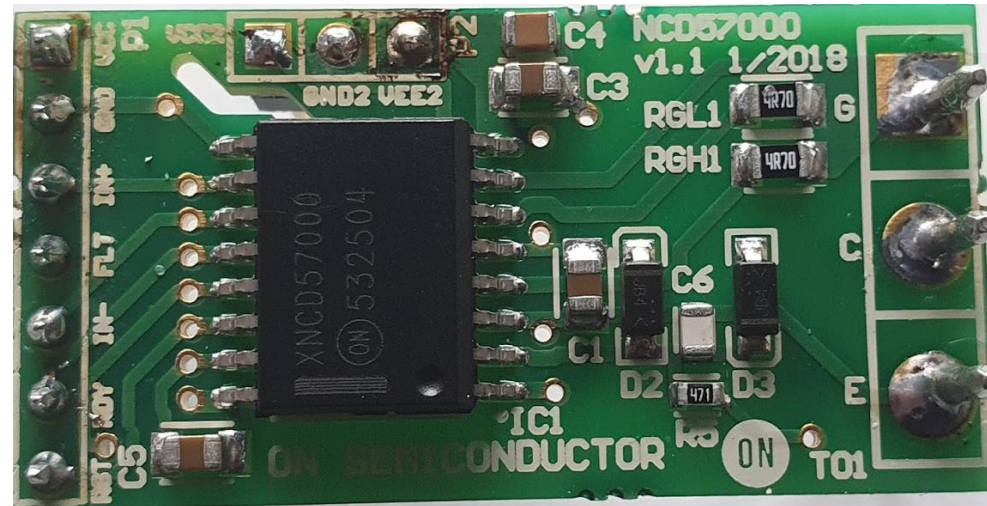


Test Procedure SECO-NCD57000-GEVB

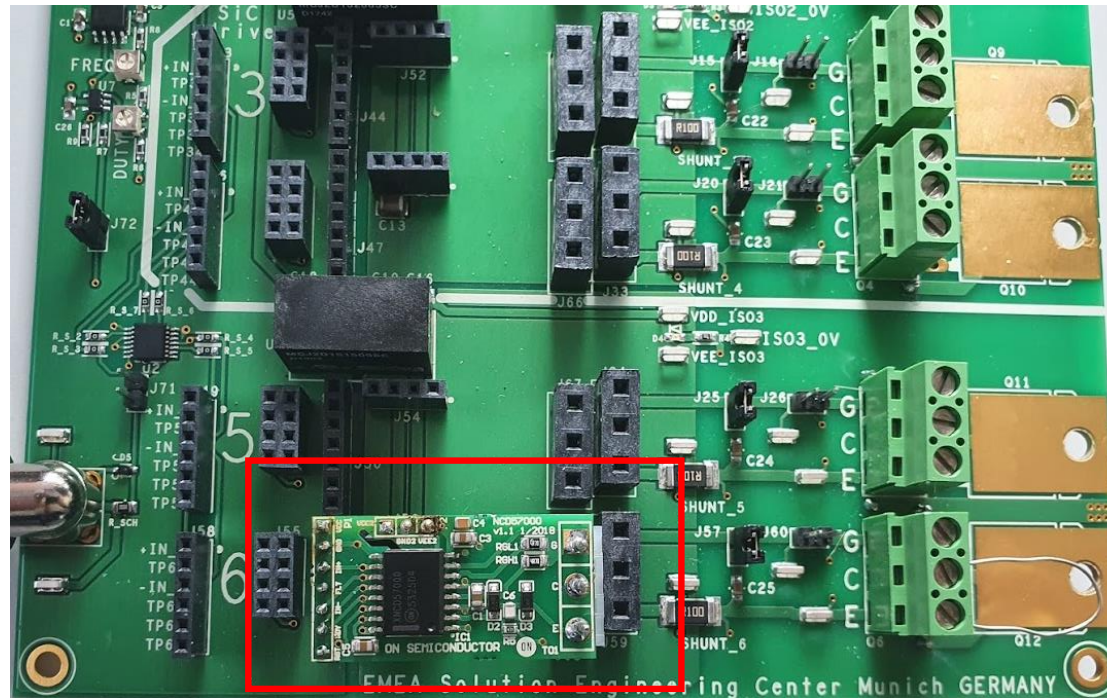
Test procedure requires

- One 4 channel oscilloscope
- 10V to 15V wall adapter for test board power supply (OD 6.5 mm)
- One test board provided by ON Semiconductor.

Device under test (DUT)



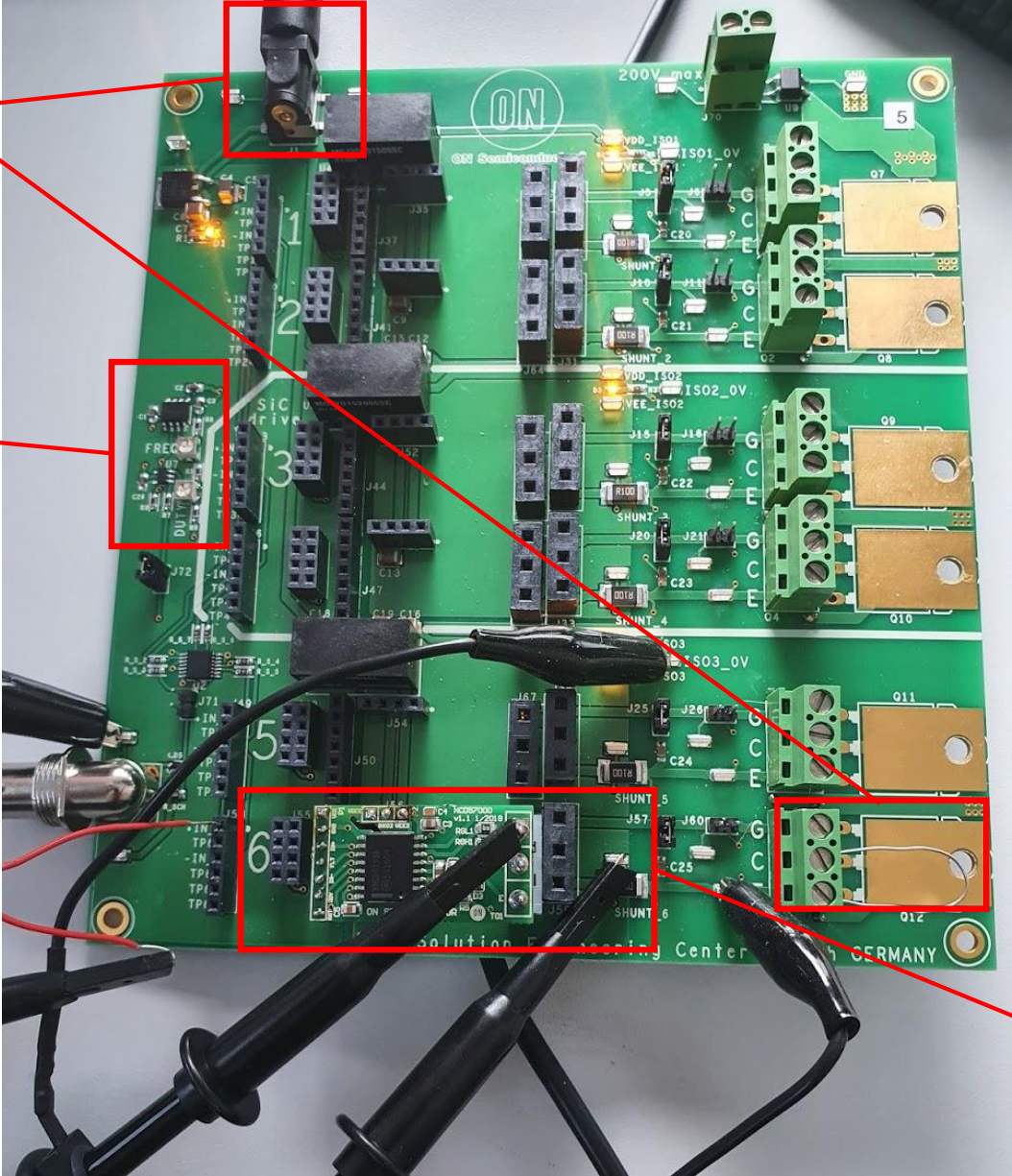
Connect DUT to channel number 6



Prepare measurement according steps below

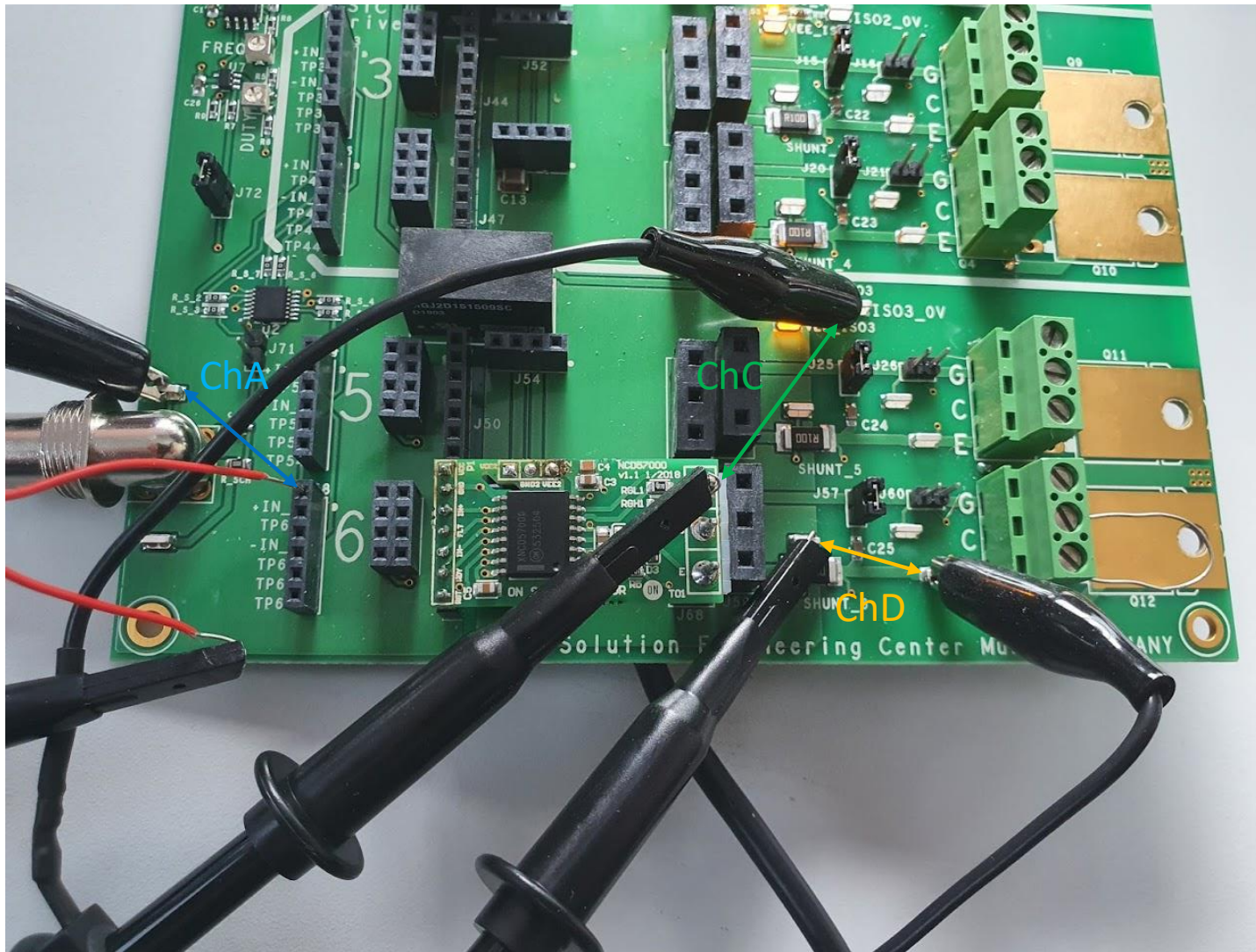
- 1) Make a short between C and E on terminal Q12
- 2) Plug 10V to 15V DC

- 3/Adjust frequency around 16 kHz (measure on opened J72)
- 4/Adjust duty cycle to 50%
- 5/ Place jumper on position J72



6/Open J60 and close J57

Measurement by scope

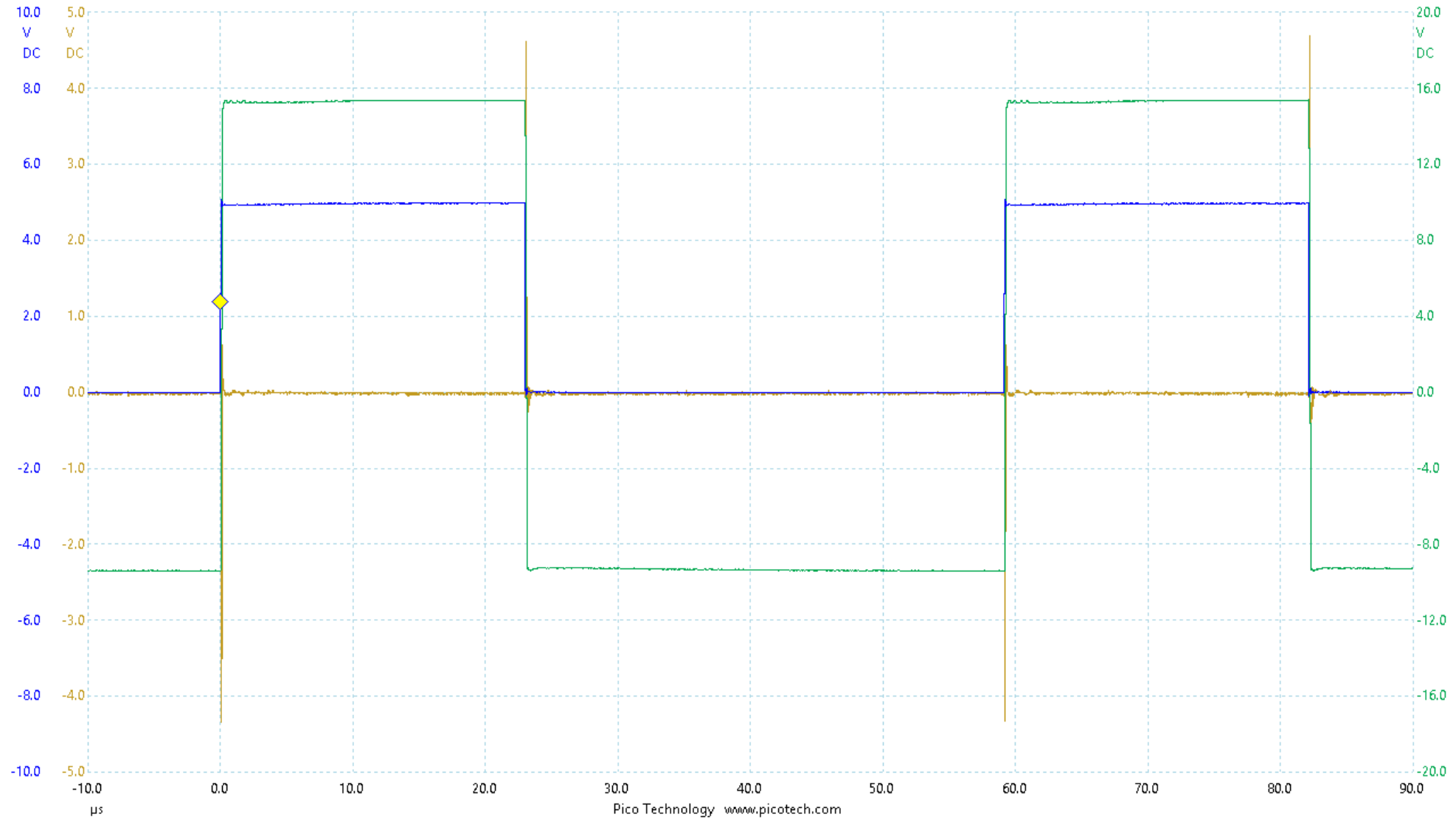


ChA: Measure voltage across J58.1 and GND on test point close to BNC connector

ChC: Measure voltage across G pin on the DUT and ISO GND on test point ISO3_0V

ChD: Measure voltage across shunt resistor SHUNT_6

Same periodic signals has to be visible



Detail for positive pulse only

